



Three-Level Physics Guided Stochastic Modeling of Nanostructure Variations in Nanomaterial Manufacturing Processes



Introduction

- In the past few years, progress in electronic devices has been driven by scaling transistors to ever-smaller dimensions motivating the search for new device concepts and new materials.
- A **grand challenge** encountered with manufacture of these nanomaterials is related to nano process repeatability as exhibited by variations in nanostructures or nano morphologies which directly impact nano device functional performance.
- The **goal** of this project is to establish a cost-effective modeling methodology for predicting and monitoring the variations in nanomanufacturing processes.

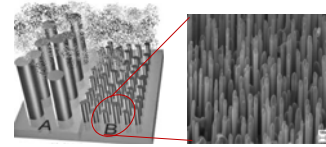


Fig. 1 Nanostructure variations in the nanowire produced for biosensors (Note the great variations of nanowire lengths)

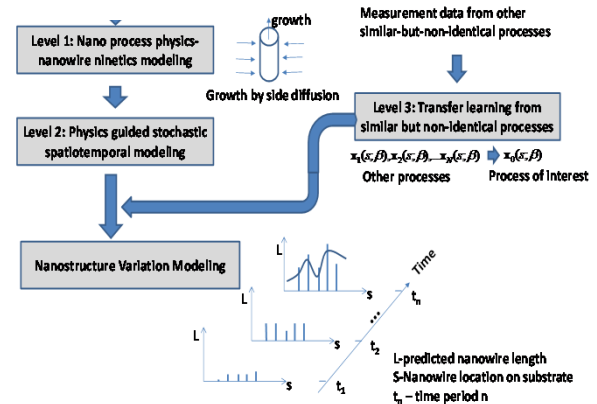


Fig. 2 A summary of the proposed modeling approach for nanostructure variations

Hypotheses & Methods

- Hypothesis 1: Commonality between similar-but-non-identical nano processes can contribute to improvement variation modeling
- Hypothesis 2: Nano process physics (nanowire growth kinetics) can supplement additional information to limited nano process data for modeling improvement.
- A three-level physics guided stochastic modeling approach will be developed to cost-effectively predict nano process variations (Fig. 3).

Highlights of findings for future

- The proposed transfer learning method can significantly improve nanowire growth prediction given limited nano process data (Fig. 3b)
- Two papers under preparation
- Target funding:
 - **National Science Foundation**. include Nanomanufacturing and SNM programs.
 - **Department of Defense**. ONR and AFOSR
 - Two NSF proposals were submitted

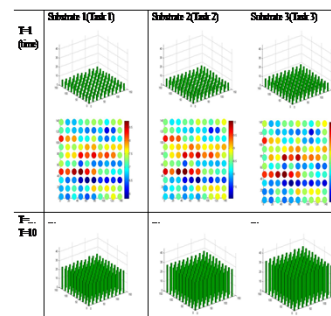


Fig. 3(a) Modeling results of nanowire growth

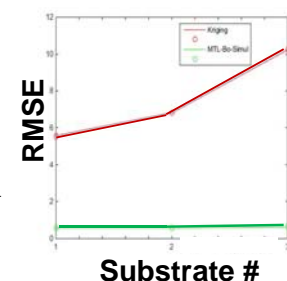
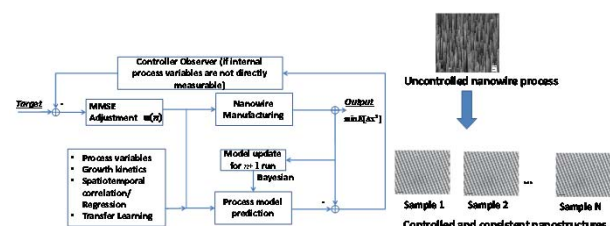


Fig. 3(b) Reduced model error
Red: Traditional method
Green: new method

Future Work

- Establishing a cost-effective quality control strategy for nanowire manufacturing
- Big data enabled intelligent nano processes



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